



CERTIFICATE OF ACCREDITATION

The ANSI National Accreditation Board

Hereby attests that

A2 Global Electronics + Solutions (America II Asia Pte Ltd)

**151 Lorong Chuan
#06-05A, #06-06, #06-07
New Tech Park 556741
Republic of Singapore**

Fulfills the requirements of

ISO/IEC 17025:2017

and

AS6171 Detection of Suspect/Counterfeit Parts Accreditation Program

In the field of

TESTING

This certificate is valid only when accompanied by a current scope of accreditation document.
The current scope of accreditation can be verified at www.anab.org.

Jason Stine, Vice President

Expiry Date: 22 December 2027

Certificate Number: AT-3054.01



This laboratory is accredited in accordance with the recognized International Standard ISO/IEC 17025:2017.
This accreditation demonstrates technical competence for a defined scope and the operation of a laboratory
quality management system (refer to joint ISO-ILAC-IAF Communiqué dated April 2017).

SCOPE OF ACCREDITATION TO ISO/IEC 17025:2017

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#06-05A, #06-06, #06-07
New Tech Park 556741
Republic of Singapore
Tony Giannetti +1 800 767 2637 x 1043

TESTING

ISO/IEC 17025 Accreditation Granted: **11 December 2025**

Certificate Number: **AT-3054.01** Certificate Expiry Date: **22 December 2027**

In recognition of a successful assessment to ISO/IEC 17025:2017 General Requirements for the competence of Testing and Calibration Laboratories, AS6171 General Requirements, and the requirements of the ANAB SR 2429 – Labs Performing Detection of Suspect/Counterfeit Parts Under AS6171 program, accreditation is granted to **A2 Global Electronics + Solutions** to perform the following AS6171 slash sheet tests:

Non-Destructive Testing

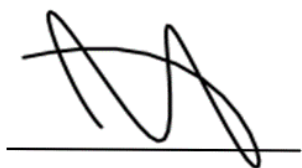
Specific Tests and/or Properties Measured	Specification, Standard, Method, or Test Technique	Items, Materials or Product Tested	Key Equipment or Technology
Visual Inspection	AS6081, 4.2.6.4 AS6171/2A	Electrical, Electronic and Electromechanical (EEE) Components	Atto Instruments, Amscope Microscope, Dinolight
Solvent Test for Remarking	AS6081 4.2.6.4.3 A AS6171/2A		Mineral spirits, Isopropyl alcohol
Dimensional Verification	AS6081, 4.2.6.4.2.2 AS6171/2A		Calipers, Contactless Measurement System
XRF	AS6081, 4.2.6.4.5 AS6171/3		Multiple X-ray fluorescence Testers
X-ray	AS6081, 4.2.6.4.4 AS6171/5		Multiple Radiological Testers
Surface Texture Analysis	AS6171/2 Method F AS6081 Sect 4.2.6.4.3 C		Scanning Electron Microscope (SEM)
Acoustic Microscopy	AS6171/6 AS6081 Appendix C.6		Scanning Acoustic Microscope (SAM)

Mechanical

Specific Tests and/or Properties Measured	Specification, Standard, Method, or Test Technique	Items, Materials or Product Tested	Key Equipment or Technology
Solvent Test for Resurfacing	AS6081 4.2.6.4.3 B AS6171/2A	Electrical, Electronic and Electromechanical (EEE) Components	Hot plate, Acetone, 1-Methyl 2-Pyrrolidinone, Dynasolve 750 or equivalent
Decapsulation	AS6081, 4.2.6.4.6 AS6171/4		Decapsulation Furnace
Solderability	ANSI/J-STD-002		Solder Pot
Solder Wetting Balance Test	ANSI/J-STD-002 MIL-STD-883		Wetting Balance Tester
Coating / Plating Analysis	AS6171/3		X-ray fluorescence Plating Thickness Tester

Electrical

Specific Tests and/or Properties Measured	Specification, Standard, Method, or Test Technique	Items, Materials or Product Tested	Key Equipment or Technology
Electrical Test	AS6171/7 Table 2 AS6081, Sect. C.3	Electrical, Electronic and Electromechanical (EEE) Components	ATE and various Electronic Lab Equipment
Electrical, Key Parameters (AC, Switching, Functional) at ambient temp.	AS6171/7 MIL-STD-883		
Electrical, DC Test and Key Parameters (AC, Switching, Functional), over temp.	AS6171/7 MIL-STD-883		



Jason Stine, Vice President